

Search Notes

Application/Control No.

10/564,380

Examiner

Len Tran

Applicant(s)/Patent under
Reexamination

DEIBL ET AL.

Art Unit

1725

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|------------------|-----------|----------|
| 164 | 448, 442, 427 | 3/17/2007 | LT |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|-------------------------|-----------|------|
| Double Patenting search | 3/17/2007 | LT |
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